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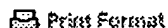
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☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Effects of random errors on the performance of antenna arrays of many elements***Rondinelli, L.;*

IRE International Convention Record , Volume: 7 , Mar 1959

Pages:174 - 189

[\[Abstract\]](#)[\[PDF Full-Text \(936 KB\)\]](#)**IEEE CNF**

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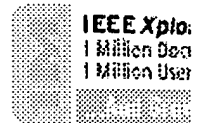
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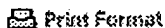
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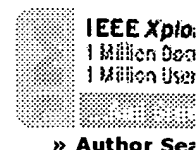
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Chiang T. H.	Chiang T. K.	Chiang T. S.	Chiang W. -C.	Chiang W. -I
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Chiang Y. -M. J.	Chiang Y. -T.	Chiang Y. -W.	Chiang Y. -Y.	Chiang Y. C.
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1 Convexity property of the one-sided multivariable stability margin

Tekawy, J.A.; Safonov, M.G.; Chiang, R.Y.;
Automatic Control, IEEE Transactions on , Volume: 37 , Issue: 4 , April 1992
Pages:496 - 498

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2 Optimal Hankel model reduction for nonminimal systems

Safonov, M.G.; Chiang, R.Y.; Limebeer, D.J.N.;
Automatic Control, IEEE Transactions on , Volume: 35 , Issue: 4 , April 1990
Pages:496 - 502

[\[Abstract\]](#) [\[PDF Full-Text \(432KB\)\]](#) **IEEE JNL**

3 A Schur method for balanced-truncation model reduction

Safonov, M.G.; Chiang, R.Y.;
Automatic Control, IEEE Transactions on , Volume: 34 , Issue: 7 , July 1989
Pages:729 - 733

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4 CACSD using the state-space L^∞ theory-a design example

Safonov, M.G.; Chiang, R.Y.;
Automatic Control, IEEE Transactions on , Volume: 33 , Issue: 5 , May 1988
Pages:477 - 479

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5 Next generation of tools for robust control

Balas, G.J.; Packard, A.K.; Safonov, M.G.; Chiang, R.Y.;
American Control Conference, 2004. Proceedings of the 2004 , Volume: 6 , June 30-July 2, 2004
Pages:5612 - 5615

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6 Automated modeling and control synthesis using the MACSYN toolbox

Bayard, D.S.; Scheid, R.E.; Chiang, R.Y.; Ahmed, A.; Mettler, E.;
American Control Conference, 1994 , Volume: 2 , 29 June-1 July 1994

Pages:1655 - 1659 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(444KB\)\]](#) [IEEE CNF](#)

7 Real/complex multivariable stability margin computation via generalized Popov multiplier-LMI approach

Ly, J.H.; Safonov, M.G.; Chiang, R.Y.;

American Control Conference, 1994 ,Volume: 1 , 29 June-1 July 1994

Pages:425 - 429 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(320KB\)\]](#) [IEEE CNF](#)

8 Structural modeling and identification using neural networks

Hadaegh, F.Y.; Chiang, R.Y.; Lin, C.-F.; Politopoulos, A.S.;

American Control Conference, 1994 ,Volume: 2 , 29 June-1 July 1994

Pages:1707 - 1711 vol.2

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9 Parametric robustness analysis for Cassini spacecraft using the LMI approach without frequency sweep

Chiang, R.Y.;

American Control Conference, 1994 ,Volume: 2 , 29 June-1 July 1994

Pages:1219 - 1222 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(252KB\)\]](#) [IEEE CNF](#)

10 Robust antenna pointing control for TDRS spacecraft

Tham, Q.; Ly, J.H.; Chiang, R.Y.; Bender, D.; Eyerly, B.N.;

Decision and Control, 1997., Proceedings of the 36th IEEE Conference on ,Volume: 5 , 10-12 Dec. 1997

Pages:4938 - 4942 vol.5

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11 Multiplier K_m/μ -analysis - LMI approach

Ly, J.H.; Chiang, R.Y.; Goh, K.C.; Safonov, M.G.;

American Control Conference, 1995. Proceedings of the ,Volume: 1 , 21-23 June 1995

Pages:431 - 436 vol.1

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12 Fuzzy logic attitude control for Cassini spacecraft

Chiang, R.Y.; Jang, J.-S.R.;

Fuzzy Systems, 1994. IEEE World Congress on Computational Intelligence., Proceedings of the Third IEEE Conference on , 26-29 June 1994

Pages:1532 - 1537 vol.3

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13 Spacecraft attitude control using nonlinear servomechanism theory

Jie Huang; Ching-Fang Lin; Hadaegh, F.Y.; Chiang, R.Y.;

Control Applications, 1994., Proceedings of the Third IEEE Conference on , 24-26 Aug. 1994

Pages:941 - 946 vol.2

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14 Structural vibration suppression using fuzzy logic control

Hadaegh, F.Y.; Chiang, R.Y.; Lin, C.-F.; Politopoulos, A.S.;

Control Applications, 1994., Proceedings of the Third IEEE Conference on , 24-26 Aug. 1994

Pages:953 - 958 vol.2

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15 /spl mu/-Synthesis Robust Control: What's wrong and how to fix it?

Safonov, M.G.; Ly, J.H.; Chiang, R.Y.;

Aerospace Control Systems, 1993. Proceedings. The First IEEE Regional Conference on , May 25-27, 1993

Pages:563 - 568

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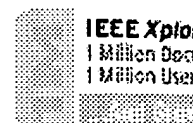
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Decision and Control, 1993., Proceedings of the 32nd IEEE Conference on , 15-17 Dec. 1993

Pages:2266 - 2271 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(440KB\)\]](#) IEEE CNF**17 H[∞] robust control synthesis for a fighter performing a coordinated bank turn***Thompson, P.M.; Chiang, R.Y.;*

Decision and Control, 1990., Proceedings of the 29th IEEE Conference on , 5-7 Dec. 1990

Pages:3362 - 3366 vol.6

[\[Abstract\]](#) [\[PDF Full-Text \(364KB\)\]](#) IEEE CNF**18 A fixed H[∞] controller for a supermaneuverable fighter performing the Herbst maneuver***Chiang, R.Y.; Safonov, M.G.; Madden, K.P.; Tekawy, J.A.;*

Decision and Control, 1990., Proceedings of the 29th IEEE Conference on , 5-7 Dec. 1990

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